



# Power MOSFETS

## DATASHEET

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**LM1A027NHV2A**

N-Channel  
Enhancement Mode MOSFET

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- [www.leadpower-semi.com](http://www.leadpower-semi.com)



Quality Management Systems  
ISO 9001:2015 Certificate

# LM1A027NHV2A

## N-Channel Enhancement Mode MOSFET

### Pin Description

TO-263-2L (TOP view)	Symbol	Symbol	N-Channel	Unit
		$V_{DSS}$	100	V
		$R_{DS(ON)-Max}$	3.1	mΩ
		ID	204	A

### Feature

- High Speed Power Switching
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

### Applications

- Synchronous Rectification in SMPS
- Hard Switching and High Speed Circuit

### Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1A027NHV2A	TO-263-2L	Tape & Reel	800 / Tape & Reel	1A027 <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/>

Note :      = Lot Code

### Absolute Maximum Ratings ( $T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
$V_{DSS}$	Drain-Source Voltage	100	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	
$T_J$	Maximum Junction Temperature	150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$I_S$	Diode Continuous Forward Current	$T_c=25^\circ\text{C}$	A
$I_D$	Pulse Drain Current Tested	$T_c=25^\circ\text{C}$	A
$I_D$	Continuous Drain Current	$T_c=25^\circ\text{C}$	A
$I_D$		$T_c=100^\circ\text{C}$	
$P_D$	Maximum Power Dissipation	$T_c=25^\circ\text{C}$	W
$P_D$		$T_c=100^\circ\text{C}$	
$I_D$	Continuous Drain Current	$T_A=25^\circ\text{C}$	A
$I_D$		$T_A=70^\circ\text{C}$	
$P_D$	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	W
$P_D$		$T_A=70^\circ\text{C}$	
$I_{AS}^{\circledR}$	Avalanche Current, Single pulse	L=0.1mH	A
$I_{AS}^{\circledR}$		L=0.5mH	
$E_{AS}^{\circledR}$	Avalanche Energy, Single pulse	L=0.1mH	mJ
$E_{AS}^{\circledR}$		L=0.5mH	

### Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{JC}$	Thermal Resistance-Junction to Case	Steady State	0.4
$R_{JA}$ <sup>③</sup>	Thermal Resistance-Junction to Ambient	Steady State	50

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in<sup>2</sup> FR-4 board with 1oz.

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## N-Channel Electrical Characteristics (T<sub>J</sub>=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Electrical Characteristics</b>						
<b>BV<sub>DSS</sub></b>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250uA	100	-	-	V
<b>I<sub>DSS</sub></b>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =80V, V <sub>GS</sub> =0V	-	-	1	uA
<b>V<sub>GS(th)</sub></b>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250uA	2	3	4	V
<b>I<sub>GSS</sub></b>	Gate Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
<b>R<sub>DS(ON)</sub><sup>④</sup></b>	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =20A	-	2.6	3.1	mΩ
<b>g<sub>fS</sub></b>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>DS</sub> =10A	-	37.6	-	S
<b>Dynamic Characteristics<sup>⑤</sup></b>						
<b>R<sub>G</sub></b>	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, Freq.=1MHz	-	0.3	-	Ω
<b>C<sub>iss</sub></b>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =50V, Freq.=1MHz	-	8532	-	pF
<b>C<sub>oss</sub></b>	Output Capacitance		-	2380	-	
<b>C<sub>rss</sub></b>	Reverse Transfer Capacitance		-	72	-	
<b>t<sub>d(ON)</sub></b>	Turn-on Delay Time	V <sub>GS</sub> =10V, V <sub>DS</sub> =25V, I <sub>D</sub> =1A , R <sub>GEN</sub> =1Ω	-	25.7	-	nS
<b>t<sub>r</sub></b>	Turn-on Rise Time		-	12.7	-	
<b>t<sub>d(OFF)</sub></b>	Turn-off Delay Time		-	69.8	-	
<b>t<sub>f</sub></b>	Turn-off Fall Time		-	131.1	-	
<b>Q<sub>g</sub></b>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =50V, I <sub>D</sub> =20A	-	147.4	-	nC
<b>Q<sub>gs</sub></b>	Gate-Source Charge		-	42.2	-	
<b>Q<sub>gd</sub></b>	Gate-Drain Charge		-	39.2	-	
<b>Source-Drain Characteristics</b>						
<b>V<sub>SD</sub><sup>④</sup></b>	Diode Forward Voltage	I <sub>SD</sub> =10A, V <sub>GS</sub> =0V	-	0.75	1.1	V
<b>t<sub>rr</sub></b>	Reverse Recovery Time	I <sub>F</sub> =10A, V <sub>R</sub> =50V	-	80.8	-	nS
<b>Q<sub>rr</sub></b>	Reverse Recovery Charge	dI <sub>F</sub> /dt=100A/μs	-	160.3	-	nC

Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

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## N-Channel Typical Characteristics

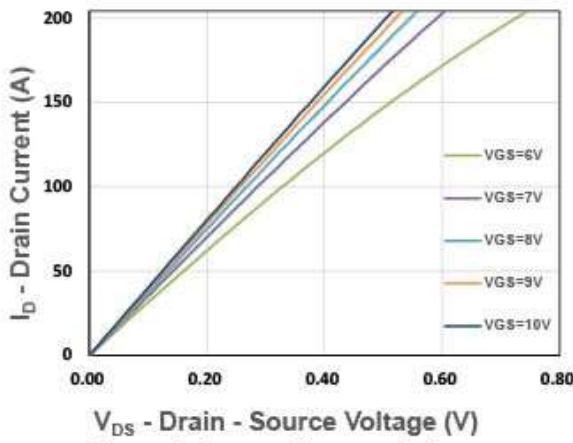


Figure 1. Output Characteristics

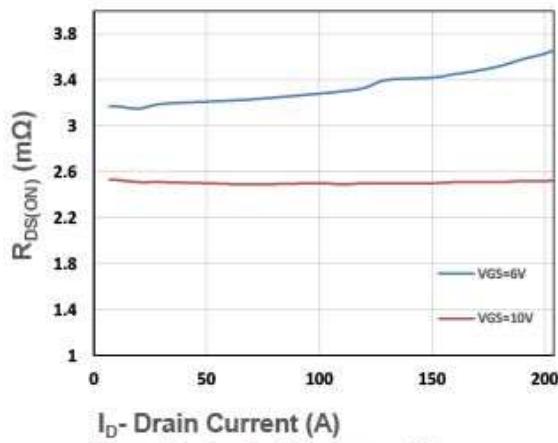


Figure 2. On-Resistance vs. ID

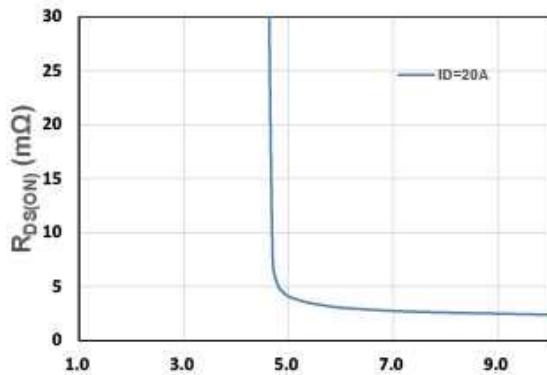


Figure 3. On-Resistance vs. VGS

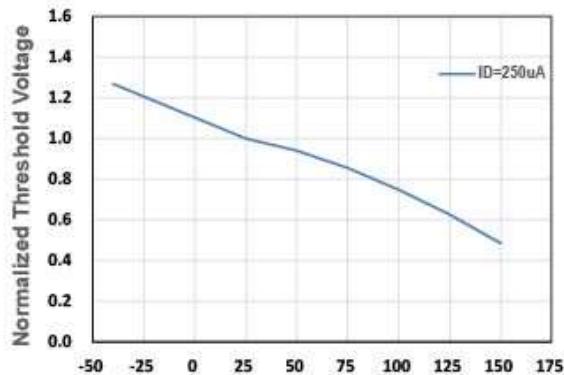


Figure 4. Gate Threshold Voltage

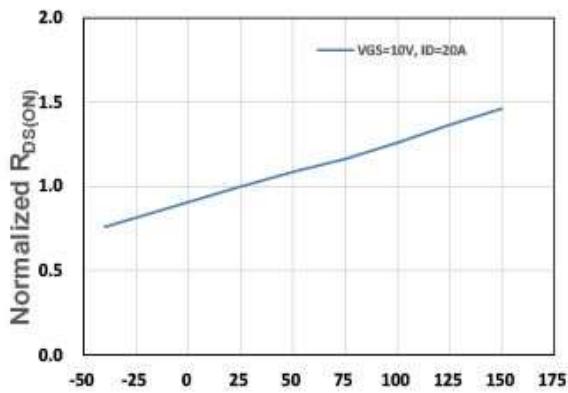


Figure 5. Drain-Source On Resistance

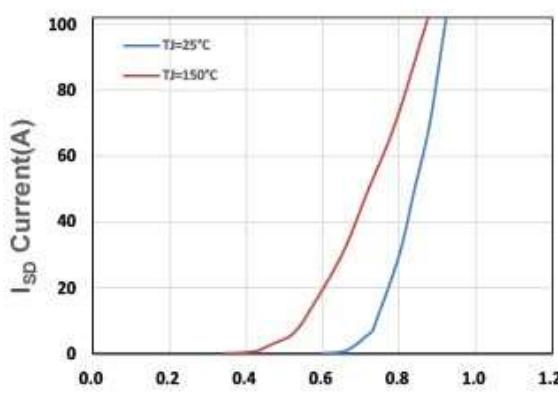
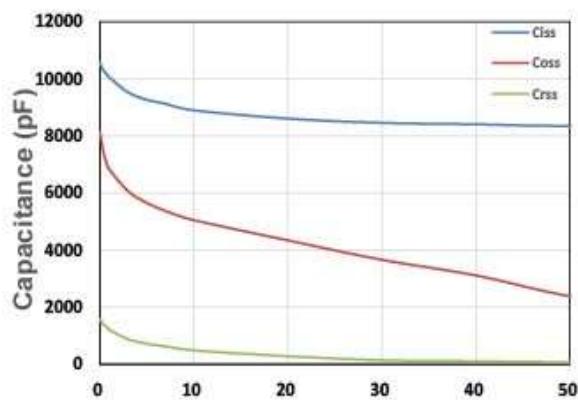


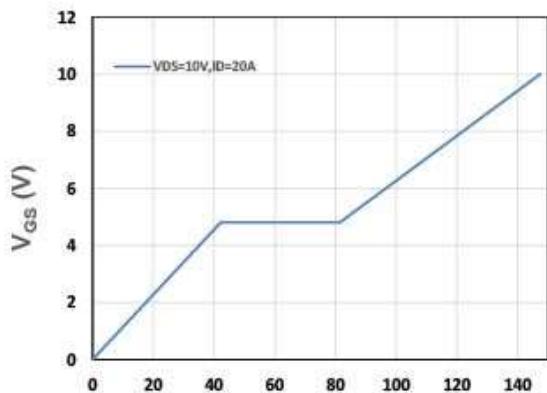
Figure 6. Source-Drain Diode Forward

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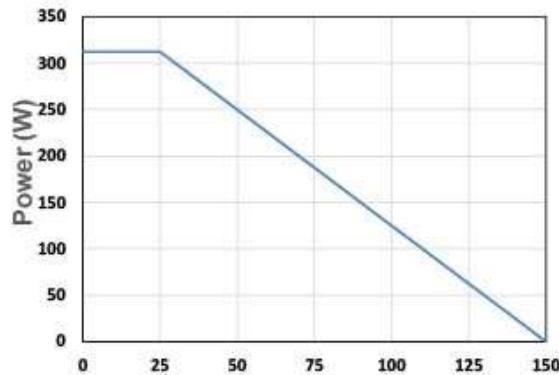
**Leadpower**  
Semiconductor



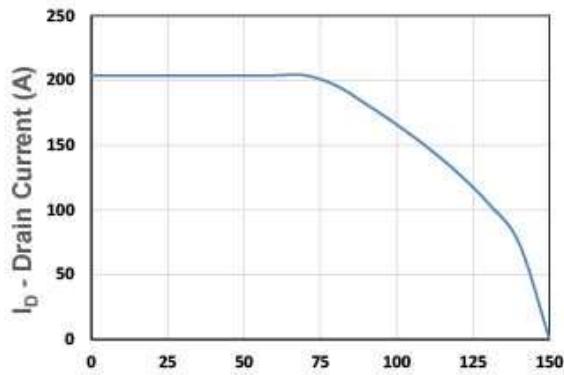
$V_{DS}$  - Drain - Source Voltage (V)  
Figure 7. Capacitance



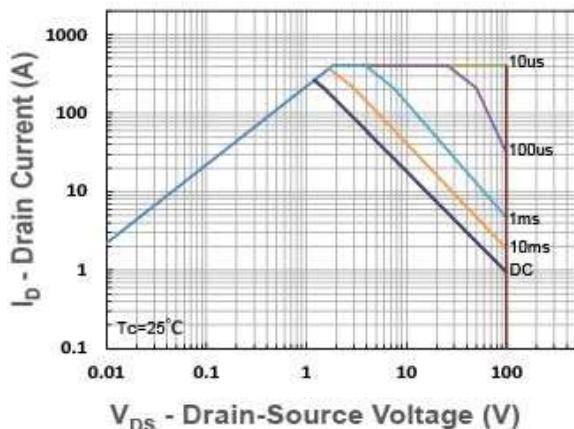
$Q_g$ , Total Gate Charge (nC)  
Figure 8. Gate Charge Characteristics



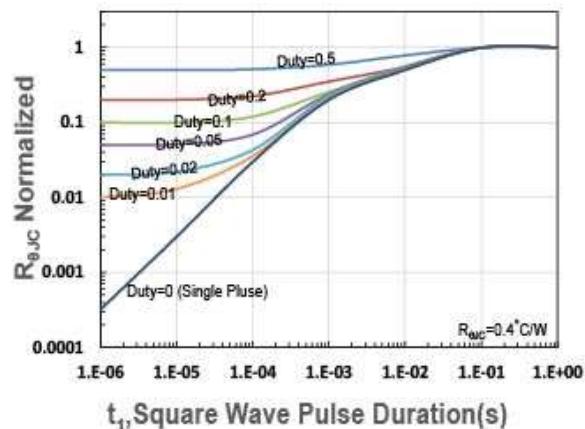
$T_c$  - Case Temperature (°C)  
Figure 9. Power Dissipation



$I_D$  - Drain Current (A)  
Figure 10. Drain Current



$V_{DS}$  - Drain-Source Voltage (V)  
Figure 11. Safe Operating Area



$R_{θJC}$  Normalized  
 $t_1$ , Square Wave Pulse Duration(s)  
Figure 12.  $R_{θJC}$  Transient Thermal Impedance